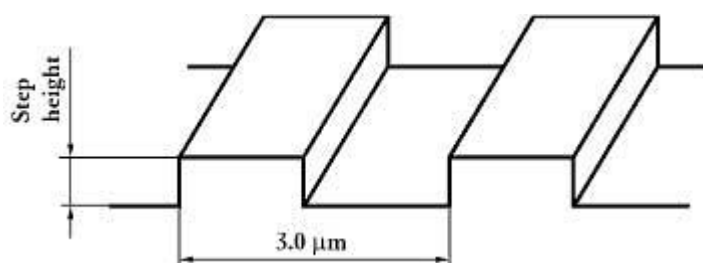
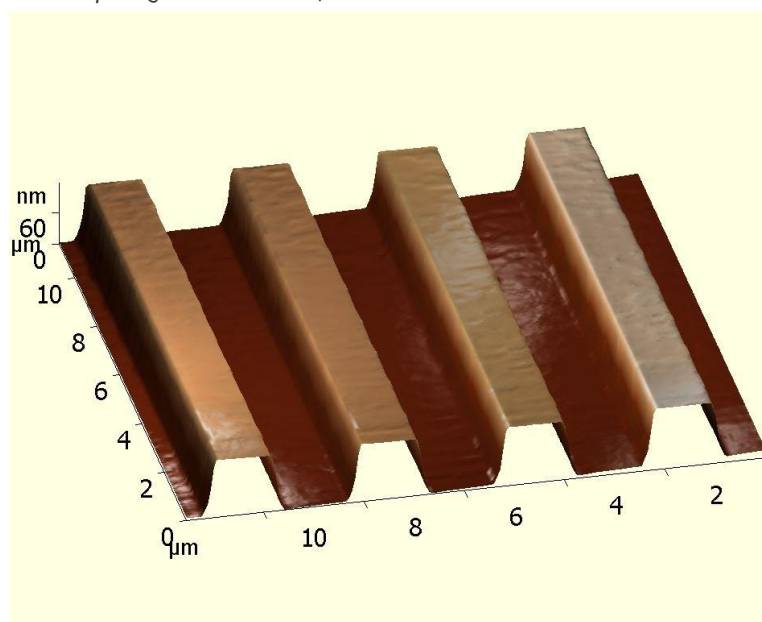


Product Description

Calibration grating TGZ1 for Z-axis calibration (step height $20,0 \pm 1.5 \text{ nm}$) and nonlinearity measurements.



Step height is the average meaning based on the measurements of 5 gratings with the same height (from the batch of 300 gratings) by AFM calibrated with help of PTB certified grating TGZ1. Basic step height can vary from the specified one within $\pm 10\%$ depending on the batch (for example TGZ1 grating can have step height $22 \pm 1.5 \text{ nm}$).



AFM image of TGZ1 grating (step height 20nm).

General Features

Structure	step - SiO ₂ , bottom - Si
Pattern type	2-Dimensional
Period	$3 \pm 0,05 \mu\text{m}$
Height	$20,0 \pm 1.5 \text{ nm}^*$
Chip size	5x5x0,5 mm
Effective area	central square 3x3 mm